

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10577919	LEE ET AL.
	Examiner	Art Unit
	MARCOS BATISTA	2617

SEARCHED

Class	Subclass	Date	Examiner
370	335	5/6/2008	mb
370	342	5/6/2008	mb

SEARCH NOTES

Search Notes	Date	Examiner
Consulted with TA - Yogesh Aggarwal	5/6/2008	mb
Consulted with Lun-YI Lao	5/6/2008	mb
Inventor's Name Seach	5/6/2008	mb
Consulted with Rafael Perez Gutierrez	10/6/2009	mb
East Search	10/6/2009	mb
Consulted with Rafael Perez Gutierrez	4/7/2010	mb
East Search	4/7/2010	mb

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
370	318, 342, 355	4/7/2010	mb
455	13.4, 522, 571	4/7/2010	mb

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